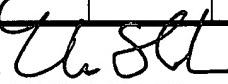
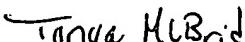
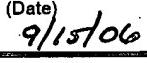


<b>Issue Classification</b>				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/616,065		JOBS ET AL.	
				Examiner		Art Unit	
				Chi Q. Nguyen		3635	

ISSUE CLASSIFICATION					
ORIGINAL		CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)		
52	188	52	179		
INTERNATIONAL CLASSIFICATION					
E	0	4	F	11/00	
				19/10	
				/	
				/	
				/	
 Chi Q. Nguyen 9/13/2006 (Assistant Examiner) (Date)				 NAOKO SLACK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3600 (Primary Examiner) (Date)  Tonya McBride 9/15/06 (Legal Instruments Examiner) (Date)	
				Total Claims Allowed: 27  9/15/06	
				O.G. Print Claim(s) 1	O.G. Print Fig. 3B

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
6	1	24	31	61	91	121	151
7	2	25	32	62	92	122	152
8	3	26	33	63	93	123	153
9	4	27	34	64	94	124	154
10	5	21	35	65	95	125	155
11	6	36	66	96		126	156
19	8	37	67	97		127	157
12	9	38	68	98		128	158
13	10	39	69	99		129	159
14	11	40	70	100		130	160
15	12	41	71	101		131	161
14	13	42	72	102		132	162
20	15	43	73	103		133	163
	16	44	74	104		134	164
1	17	45	75	105		135	165
2	18	46	76	106		136	166
3	19	47	77	107		137	167
4	20	48	78	108		138	168
5	21	49	79	109		139	169
18	22	50	80	110		140	170
	23	51	81	111		141	171
	24	52	82	112		142	172
	25	53	83	113		143	173
	26	54	84	114		144	174
	27	55	85	115		145	175
16	28	56	86	116		146	176
17	29	57	87	117		147	177
22	30	58	88	118		148	178
		59	89	119		149	179
		60	90	120		150	180